## Notice of References Cited Application/Control No. 10/613,598 Examiner Tianjie Chen Applicant(s)/Patent Under Reexamination TAKANO, KENICHI Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0047087 A1	03-2004	Fukui et al.	360/324.12
	В	US-2003/0189802 A1	10-2003	Morinaga et al.	360/324.12
	С	US-6,385,017 B1	05-2002	Min et al.	360/324.12
	D	US-US 20040223269A1	11-2004	Wang et al.	360/324.12
	Ε	US-2004/0141261 A1	07-2004	Hasegawa et al.	360/324.11
	F	US-2003/0202295 A1	10-2003	Wang et al.	360/324.12
	G	US-6,731,478 B2	05-2004	Nakamoto et al.	360/324.1
	Н	US-6,633,466 B2	10-2003	Sakaguci et al.	360/327.31
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q		,		;	
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	•

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.